

**Search Notes**

Application/Control No.

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Examiner

Anh T.N. Vo

Applicant(s)/Patent under  
Reexamination

HAAN ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
npcl/ntcl Search 10/05 mv			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR